

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
ASMEX.291AAPPLICATION NO.
10/074,563INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT
Todd et al.FILING DATE
February 11, 2002GROUP
1762

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
Tim	5,389,570	02/14/95	Shiozawa	-	-	-

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

EXAMINER
INITIAL

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

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EXAMINER

DATE CONSIDERED

8/2/04

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
Thm	5,214,002	05/25/93	Hayashi Yutaka et al.	-	-	-

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

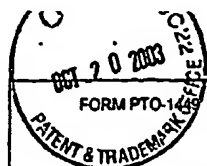
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

EXAMINER INITIAL	
	International Search Report dated 11/13/03 for international patent application no. PCTUS02/02921, filed on February 1, 2002.

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EXAMINER	DATE CONSIDERED
<i>[Signature]</i>	8/2/04

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FORM PTO-14

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1762

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
Tjm	1.	5,389,398	02/14/95	Suzuki et al.	427	130	✓
	2.	5,698,771	12/16/97	Shields et al.	73	31.05	✓
	3.	6,228,181	05/08/01	Yamamoto et al.	148	33.5	✓
	4.	6,326,311	12/04/01	Ueda et al.	438	694	✓
	5.	6,455,892	09/24/02	Okuno et al.	257	328	✓
Tjm	6.	6,613,695	09/02/03	Pomarede et al.	438	767	✓

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

EXAMINER
INITIAL

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

Tjm	7.	Ikoma et al., Growth of Si/3C-SiC/Si(100) heterostructures by pulsed supersonic free jets, Applied Physics Letters, Volume 75, No. 25, Pp. 3977-3979, December 1999					

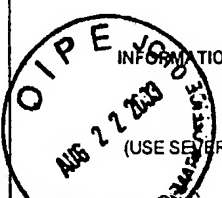
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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
1. <i>THM</i>	5,214,002	05/25/93	Hayashi et al.	✓	—	—
2. <i> </i>	5,356,821	10/18/94	Naruse et al.	—	—	—
3. <i> </i>	5,471,330	11/28/95	Sarma	—	—	—
4. <i>THM</i>	6,103,600	08/15/00	Ueda et al.	—	—	—

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
5. <i>THM</i>	11317530	16-11-99	Japan (abstract)	—	—	X	
6. <i> </i>	EP 0368651 A2	16-05-90		—	—		
7. <i> </i>	EP 0486047 A2	20-05-92		—	—		
8. <i> </i>	EP 0747974 A2	11-12-96		—	—		
9. <i> </i>	EP 1065728 A2	03-01-01		—	—		
10. <i>THM</i>	GB 2332564 A	23-06-99	United Kingdom	—	—		

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
11. <i>THM</i>	Olivares, J. et al.; "Solid-phase crystallization of amorphous SiGe films deposited by LPCVD on SiO ₂ and glass," Thin Solid Films 337 (1999) pp. 51-54.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
THM	US 2002/0098627 A1	07/25/02	Pomarede et al.	438	149	08/31/01

FOREIGN PATENT DOCUMENTS

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						YES	NO

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OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

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8/2/02

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
THM	6,159,828	12/12/00	Ping et al.	438	486	
I	6,171,662 B1	01/09/01	Nakao	427	595	
THM	6,197,669 B1	03/06/01	Twu et al.	438	585	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

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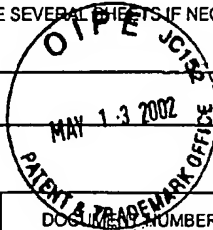
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8/2/84

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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
<i>THM</i>	4,363,828	12/14/82	Brodsky et al.			
	4,495,218	1/22/85	Azuma et al.			
	4,585,671	4/29/86	Kitagawa et al.			
	4,684,542	8/4/87	Jasinski et al.			
	5,227,329	7/13/93	Kobayashi et al.			
	5,607,724	3/4/97	Beinglass et al.			
	5,614,257	3/25/97	Beinglass et al.			
	5,648,293	7/15/97	Hayama et al.			
	5,656,531	8/12/97	Thakur et al.			
	5,695,819	12/9/97	Beinglass et al.			
	5,700,520	12/23/97	Beinglass et al.			
	5,786,027	7/28/98	Rolfson			
	5,789,030	8/4/98	Rolfson			
	5,837,580	11/17/98	Thakur et al.			
	5,874,129	2/23/99	Beinglass et al.			
	5,876,797	3/2/99	Beinglass et al.			
	5,885,869	3/23/99	Tumer et al.			
	6,027,705	2/22/00	Kitsuno et al.			11/30/98
	6,083,810	7/4/00	Obang et al.			12/5/96
<i>THM</i>	6,197,694 B1	3/6/01	Beinglass			7/31/98

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<i>THM</i>	57209810 A	12/23/82	Japan			Abstract	
	59078918 A	5/8/84	Japan			Abstract	
<i>THM</i>	59078919 A	5/8/84	Japan			Abstract	

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FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<i>TL</i>	60043485 A	3/8/85	Japan			Abstract	
	61153277 A	7/11/88	Japan			Abstract	
	62076612 A	4/8/87	Japan			Abstract	
	63003414 A	1/8/88	Japan			Abstract	
	63003463 A	1/8/88	Japan			Abstract	
	01217956 A	8/31/89	Japan			Abstract	
	01268064 A	10/25/89	Japan			Abstract	
	02155225 A	6/14/90	Japan			Abstract	
	03091239 A	4/16/91	Japan			Abstract	
	03185817 A	8/13/91	Japan			Abstract	
	03187215 A	8/15/91	Japan			Abstract	
	03292741 A	12/24/91	Japan			Abstract	
	04323834 A	11/13/92	Japan			Abstract	
	05021378 A	1/29/93	Japan			Abstract	
	05062911 A	3/12/93	Japan			Abstract	
	07249618 A	9/26/95	Japan			Abstract	
	08242006 A	9/17/96	Japan			Abstract	
	S60-43485	3/8/85	Japan (Patent Disclosure)			X	
	H 02-155225	6/14/90	Japan (Patent Disclosure)			X	
	H3-185817	8/13/91	Japan (Patent Disclosure)			X	
	H3-187215	8/15/91	Japan (Patent Disclosure)			X	
	H3-91239	4/16/91	Japan (Patent Disclosure)			X	
<i>TL</i>	H5-62911	3/12/93	Japan (Patent Disclosure)			X	

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